

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Peter J. Zdebel
FILED: Concurrently Herewith
FOR: HIGH ENERGY ESD STRUCTURE AND METHOD
Date: 12/29/2003

DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.56

Honorable Assistant Commissioner for Patents
Washington, D.C. 20231

SIR:

It is respectfully requested that the prior art listed on FORM PTO-1449 be considered in the examination of the subject application and made of record therein. A copy of the listed prior art is enclosed herewith.

No representation is made or intended that the listed prior art enclosed herewith is material to patentability of the subject patent application.

No representation is made or intended that a search has been made or that no better prior art than that listed is available.

Respectfully submitted,
Peter J. Zdebel et al



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Form PTO-
1449

LIST OF PATENTS AND PUBLICATIONS
FOR
APPLICANT'S INFORMATION
DISCLOSURE
STATEMENT
(Use Several Sheets if Necessary)

ATTY. DOCKET NO.	SERIAL NO.
Ons00535	
APPLICANT Peter Zdebel et al	
FILING DATE	GROUP
Concurrently herewith	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document #	Date	Country	Class/subclass	Translation Yes - No
AM					
AN					
AO					
AP					
AQ					
AR					

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AS	V. Vashchenko et al., "Comparison of ESD Protection Capability of Lateral BJT, SCR, and bi-directional SCR for Hi-Voltage BiCMOS Circuits," IEEE Bipolar/BiCMOS Circuits and Technology Meeting, pages 181-184, September 29 – October 1, 2002.
AT	Haigang Feng, et al., "An ESD Protection Circuit for Mixed-Signal ICs," IEEE 2001 Custom Integrated Circuits Conference, pages 493-496, May 6-9, 2001.
AU	Ke Gong et al., "A Study of Parasitic Effects of ESD Protection on RF ICs," IEEE Transactions on Microwave Theory and Techniques, Vol. 50, No. 1, pages 393-402, January 2002.
AV	H.G. Feng et al., "Circular Under-Pad Multiple Mode ESD Protection Structure for ICs," Electronics Letters, Vol. 38, No. 11, pages 511-513, May 23, 2002.
AW	Guang Chen et al., "A Systematic Study of ESD Protection Structures for RF ICs," 2003 IEEE Radio Frequency Integrated Circuits Symposium, pages 347-350, June 8-10, 2003.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.